

IN THE SPECIFICATION:

On page 12, line 24, to page 14, line 12, please amend the paragraph to read as follows:

Fig. 1 schematically presents the design of an exemplary embodiment of a transmitted light scanner according to the invention. Two multi-colored LED arrays 1 and 2, whose light paths are combined using a beam splitter 3, are used as illumination devices. For example, LED array 1 is made up of red and green LEDs, whose light is focused using a lens array 4 arranged in series. LED array 2, on the other hand, includes infrared and blue LEDs whose light is focused as well, using a lens array 5 arranged in series, and then guided to the beam splitter 3. The multi-colored light that is combined at the dichroic beam splitter 3 is guided through the mask of the film stage 7 to the image sample 8 using a condenser lens 6. The multi-colored light penetrating the film stage 8 7 is focused by a reproducing lens 9 onto a beam splitter prism complex 10, from where it is redirected onto various CCD arrays. It is apportioned to the respective CCD arrays corresponding to the respective spectral components such that the red color component is

reproduced on the CCD array 11, for example, the green color component on the CCD array 12, the blue color component on the CCD array 13, and finally the infrared spectral component on the CCD array 14, for example. At the respective CCD arrays 11, 12 and 13, the color components are then converted to image signals, and at CCD array 14, the color signal is converted to a defect signal. The original image signals are stored in a memory device 15. Low-pass signals are obtained from the color signals at a computing unit 16. The defect signal is at the same time compared to a threshold value in an additional computing unit with a connected memory unit 17, and the defect signals that exceed the threshold value are stored or processed directly. The image, low-pass and defect signals present in the memory or computing units 15, 16 and 17 are combined in a correction device 18. In doing so, either the image signal of the pixel or the low-pass signal of the pixel or a combination of image and low-pass signal is assigned to each pixel corresponding to the value of the defect signal of this pixel. In this manner, an image signal of the original is allocated to pixels that stem from areas of the picture

that are not defective, while low-pass signals replace defective areas.